



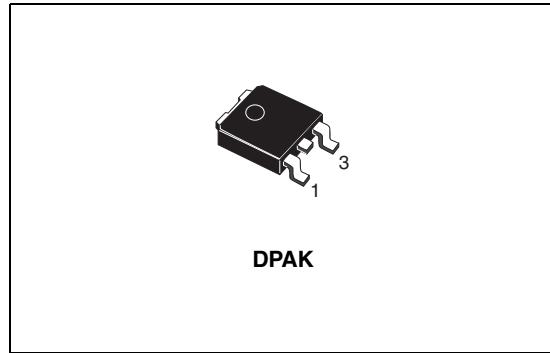
# STD16NE10L

N-channel 100V - 0.07Ω - 16A - DPAK  
STripFET™ Power MOSFET

## General features

Type	V <sub>DSS</sub>	R <sub>DS(on)</sub>	I <sub>D</sub>
STD16NE10L	100V	<0.10Ω	16A

- Avalanche rugged technology
- Low gate charge
- High current capability
- 175°C operating temperature
- Low threshold drive



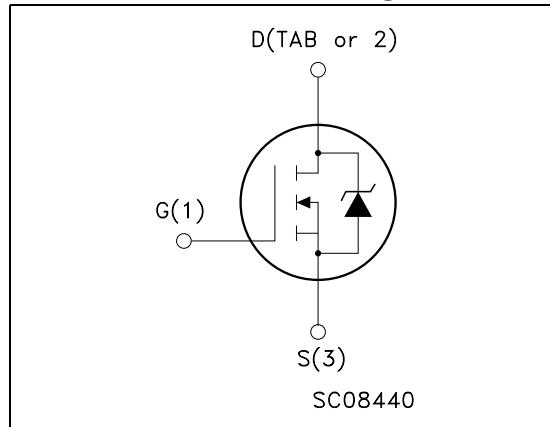
## Description

This Power MOSFET is the latest development of STMicroelectronics unique "Single Feature Size™" strip-based process. The resulting transistor shows extremely high packing density for low on-resistance, rugged avalanche characteristics and less critical alignment steps therefore a remarkable manufacturing reproducibility.

## Applications

- Switching application

## Internal schematic diagram



## Order codes

Part number	Marking	Package	Packaging
STD16NE10LT4	D16NE10L	DPAK	Tape & reel

## Contents

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# 1 Electrical ratings

**Table 1. Absolute maximum ratings**

Symbol	Parameter	Value	Unit
$V_{DS}$	Drain-source voltage ( $V_{GS} = 0$ )	100	V
$V_{DGR}$	Drain-gate voltage ( $R_{GS} = 20K\Omega$ )	100	V
$V_{GS}$	Gate-source voltage	$\pm 20$	V
$I_D$	Drain current (continuous) at $T_C = 25^\circ C$	16	A
$I_D$	Drain current (continuous) at $T_C=100^\circ C$	11	A
$I_{DM}^{(1)}$	Drain current (pulsed)	64	A
$P_{TOT}$	Total dissipation at $T_C = 25^\circ C$	90	W
	Derating factor	0.6	W/ $^\circ C$
$E_{AS}^{(2)}$	Single pulse avalanche energy	75	mJ
$dv/dt^{(3)}$	Peak diode recovery voltage slope	7	V/ns
$T_{stg}$	Storage temperature	-55 to 175	$^\circ C$
$T_J$	Max. operating junction temperature		

1. Pulse width limited by safe operating area
2. Starting  $T_J = 25^\circ C$ ,  $I_D = 8A$ ,  $V_{DD} = 30V$
3.  $I_{SD} \leq 16A$ ,  $di/dt \leq 300 A/\mu s$ ,  $V_{DS} \leq V_{(BR)DSS}$ ,  $T_J \leq T_{JMAX}$

**Table 2. Thermal data**

Symbol	Parameter	Value	Unit
$R_{thJC}$	Thermal resistance junction-case Max	1.67	$^\circ C/W$
$R_{thJA}$	Thermal resistance junction-ambient Max	100	$^\circ C/W$
$T_I$	Maximum lead temperature for soldering purpose	275	$^\circ C$

## 2 Electrical characteristics

( $T_{CASE} = 25^\circ\text{C}$  unless otherwise specified)

**Table 3. On<sup>(1)</sup> /off states**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$I_D = 250\mu\text{A}, V_{GS} = 0$	100			V
$I_{DSS}$	Zero gate voltage drain current ( $V_{GS} = 0$ )	$V_{DS} = \text{Max rating}$ $V_{DS} = \text{Max rating}, T_C = 125^\circ\text{C}$			1 10	$\mu\text{A}$ $\mu\text{A}$
$I_{GSS}$	Gate body leakage current ( $V_{DS} = 0$ )	$V_{GS} = \pm 20\text{V}$			$\pm 100$	nA
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1	1.7	2.5	V
$R_{DS(\text{on})}$	Static drain-source on resistance	$V_{GS} = 10\text{V}, I_D = 8\text{A}$ $V_{GS} = 5\text{V}, I_D = 8\text{A}$		0.07 0.085	0.085 0.01	$\Omega$ $\Omega$

1. Pulsed: Pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%

**Table 4. Dynamic**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$g_{fs}^{(1)}$	Forward transconductance	$V_{DS} > I_{D(\text{on})} \times R_{DS(\text{on})\text{max}}$ $I_D = 8\text{A}$	5	9		s
$C_{iss}$ $C_{oss}$ $C_{rss}$	Input capacitance Output capacitance Reverse transfer capacitance	$V_{DS} = 25\text{V}, f = 1 \text{ MHz}, V_{GS} = 0$		1750 165 45		pF pF pF
$Q_g$ $Q_{gs}$ $Q_{gd}$	Total gate charge Gate-source charge Gate-drain charge	$V_{DD} = 80\text{V}, I_D = 16\text{A}$ $V_{GS} = 5\text{V}$		24 5.5 11	32	nC nC nC

1. Pulsed: pulse duration=300 $\mu\text{s}$ , duty cycle 1.5%

**Table 5. Switching times**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(\text{on})}$ $t_r$ $t_{d(\text{off})}$ $t_f$	Turn-on delay time Rise time Turn-off delay time Fall time	$V_{DD} = 50\text{V}, I_D = 8\text{A}, R_G = 4.7\Omega, V_{GS} = 4.5\text{V}$ <i>Figure 12 on page 8</i>		40 80 45 12		ns ns ns ns
$t_{r(V_{off})}$ $t_f$ $t_c$	Off-voltage Rise Time Fall Time Cross-over Time	$V_{clamp} = 80 \text{ V}, I_D = 16 \text{ A}$ $R_G = 4.7\Omega, V_{GS} = 4.5 \text{ V}$ (Inductive Load, Figure 5)		12 17 35		ns ns ns

**Table 6. Source drain diode**

Symbol	Parameter	Test conditions	Min	Typ.	Max	Unit
$I_{SD}$	Source-drain current				16	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)				64	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 16A, V_{GS} = 0$			1.5	V
$t_{rr}$ $Q_{rr}$ $I_{RRM}$	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_{SD} = 16A,$ $di/dt = 100A/\mu s,$ $V_{DD} = 40V, T_J = 150^\circ C$ <i>Figure 14 on page 8</i>		100 300 6		ns $\mu C$ A

1. Pulse width limited by safe operating area.
2. Pulsed: pulse duration=300 $\mu s$ , duty cycle 1.5%

## 2.1 Electrical characteristics (curves)

Figure 1. Safe operating area

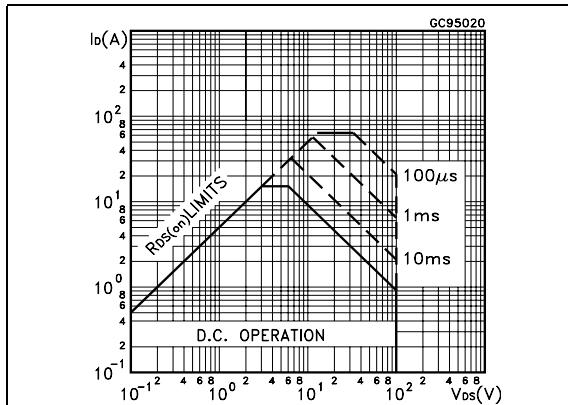


Figure 2. Thermal impedance

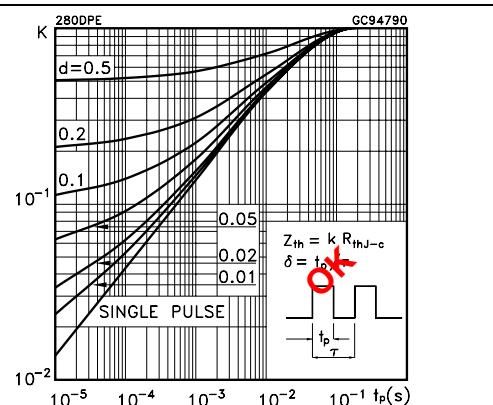


Figure 3. Output characteristics

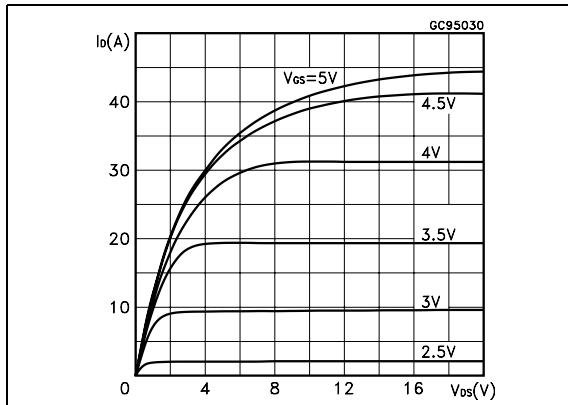


Figure 4. Transfer characteristics

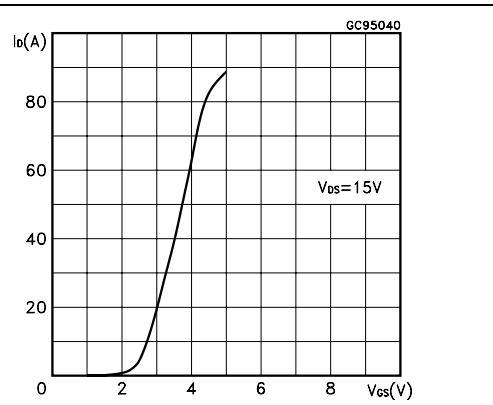


Figure 5. Transconductance

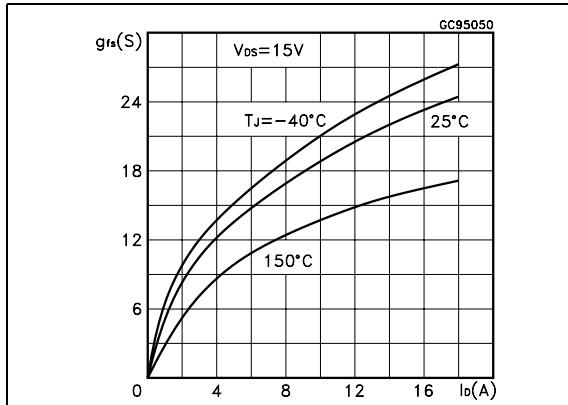
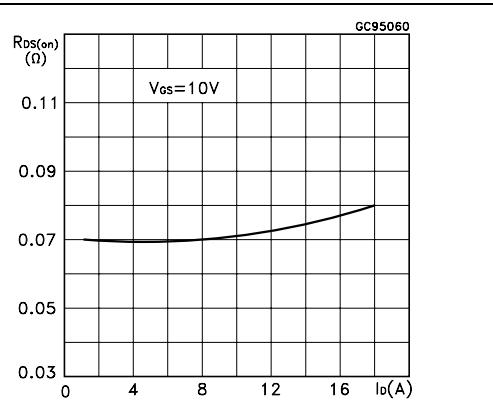
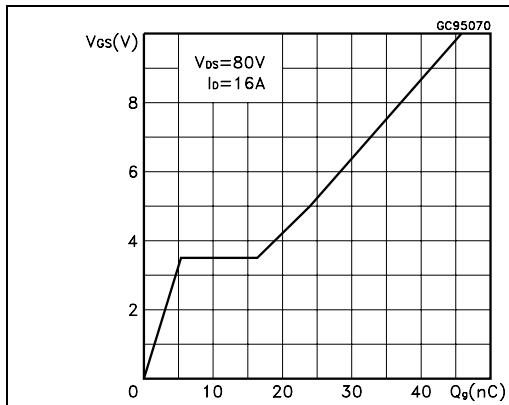
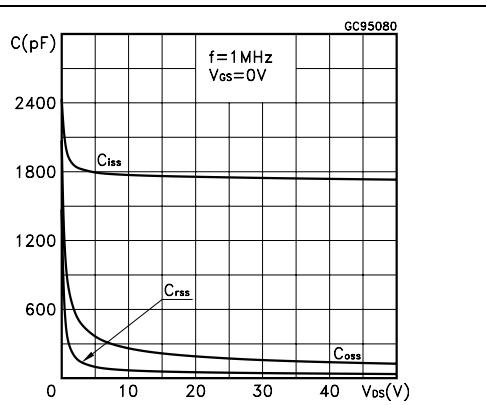
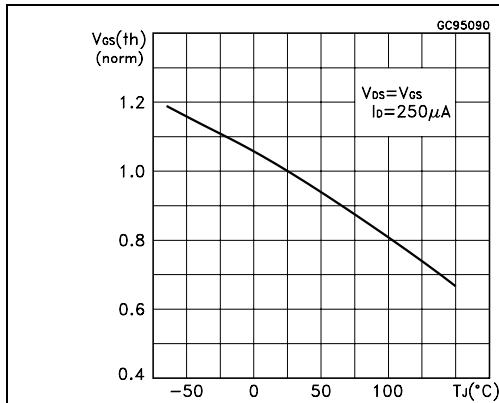
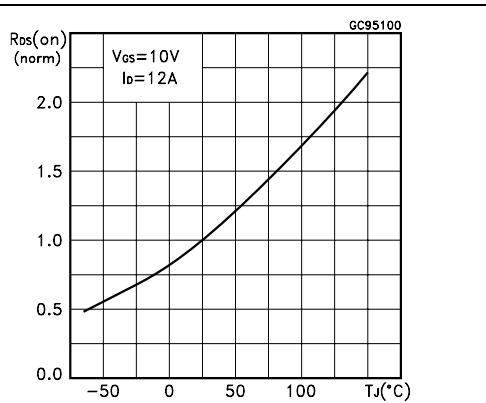
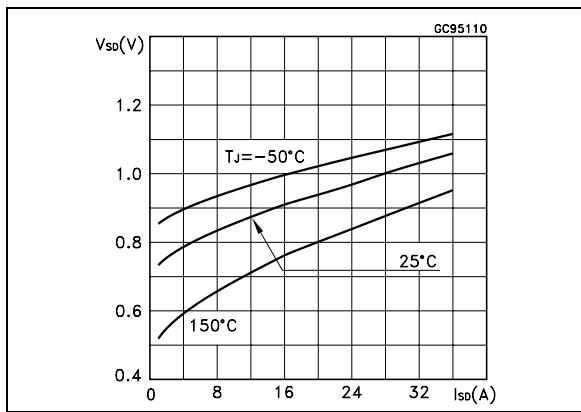
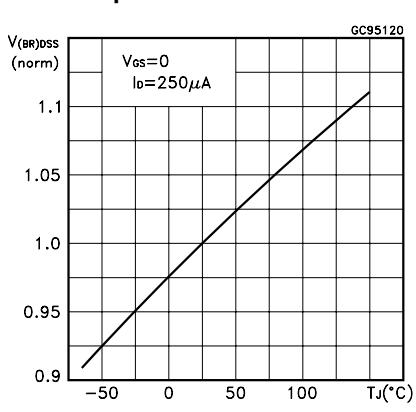


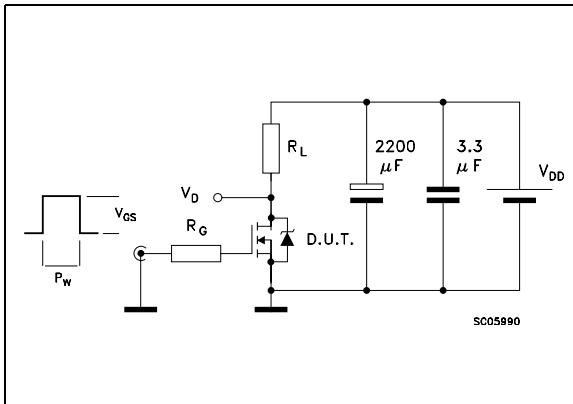
Figure 6. Static drain-source on resistance



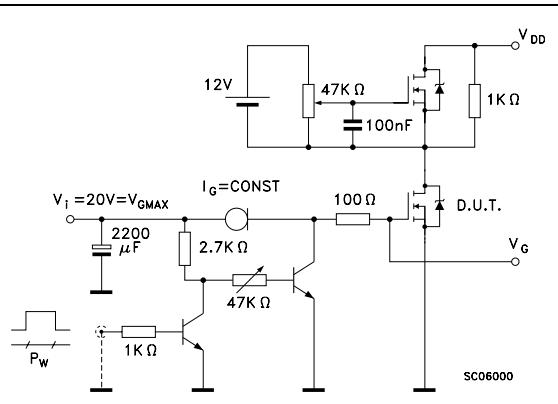
**Figure 7. Gate charge vs. gate-source voltage****Figure 9. Normalized gate threshold voltage vs. temperature****Figure 8. Capacitance variations****Figure 10. Normalized on resistance vs. temperature****Figure 11. Source-drain diode forward characteristics****Table 7. Normalized breakdown voltage temperature**

### 3 Test circuit

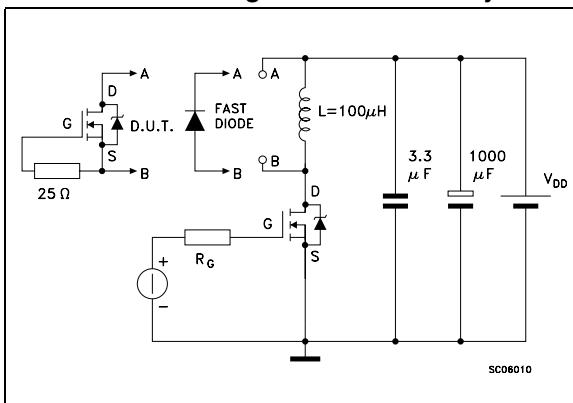
**Figure 12. Switching times test circuit for resistive load**



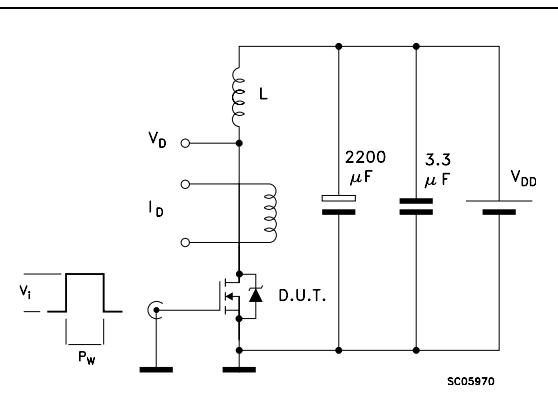
**Figure 13. Gate charge test circuit**



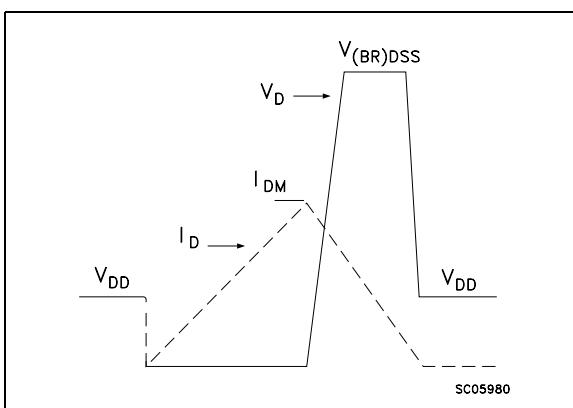
**Figure 14. Test circuit for inductive load switching and diode recovery times**



**Figure 15. Unclamped Inductive load test circuit**



**Figure 16. Unclamped inductive waveform**



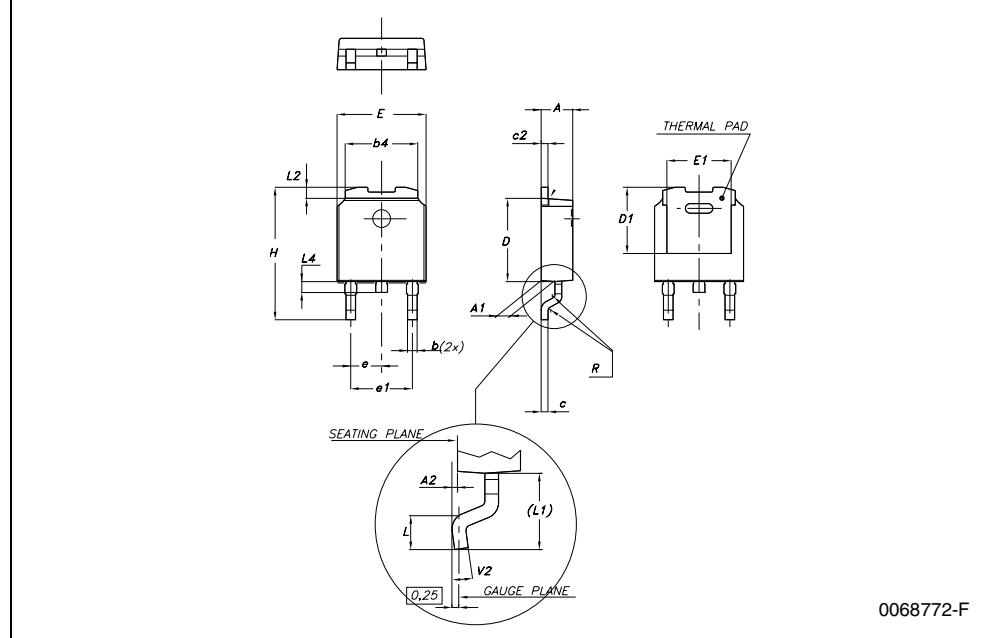
## 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect. The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: [www.st.com](http://www.st.com)



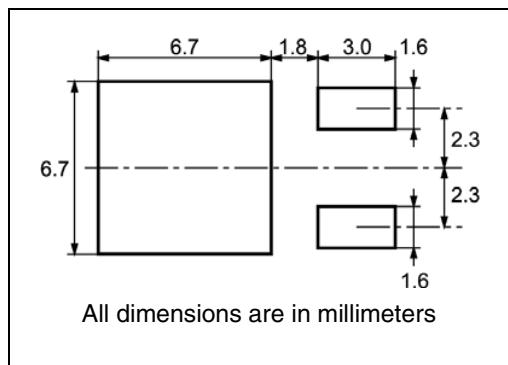
## DPAK MECHANICAL DATA

DIM.	mm.			inch		
	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
A	2.2		2.4	0.086		0.094
A1	0.9		1.1	0.035		0.043
A2	0.03		0.23	0.001		0.009
B	0.64		0.9	0.025		0.035
b4	5.2		5.4	0.204		0.212
C	0.45		0.6	0.017		0.023
C2	0.48		0.6	0.019		0.023
D	6		6.2	0.236		0.244
D1		5.1			0.200	
E	6.4		6.6	0.252		0.260
E1		4.7			0.185	
e		2.28			0.090	
e1	4.4		4.6	0.173		0.181
H	9.35		10.1	0.368		0.397
L	1			0.039		
(L1)		2.8			0.110	
L2		0.8			0.031	
L4	0.6		1	0.023		0.039
R		0.2			0.008	
V2	0°		8°	0°		8°

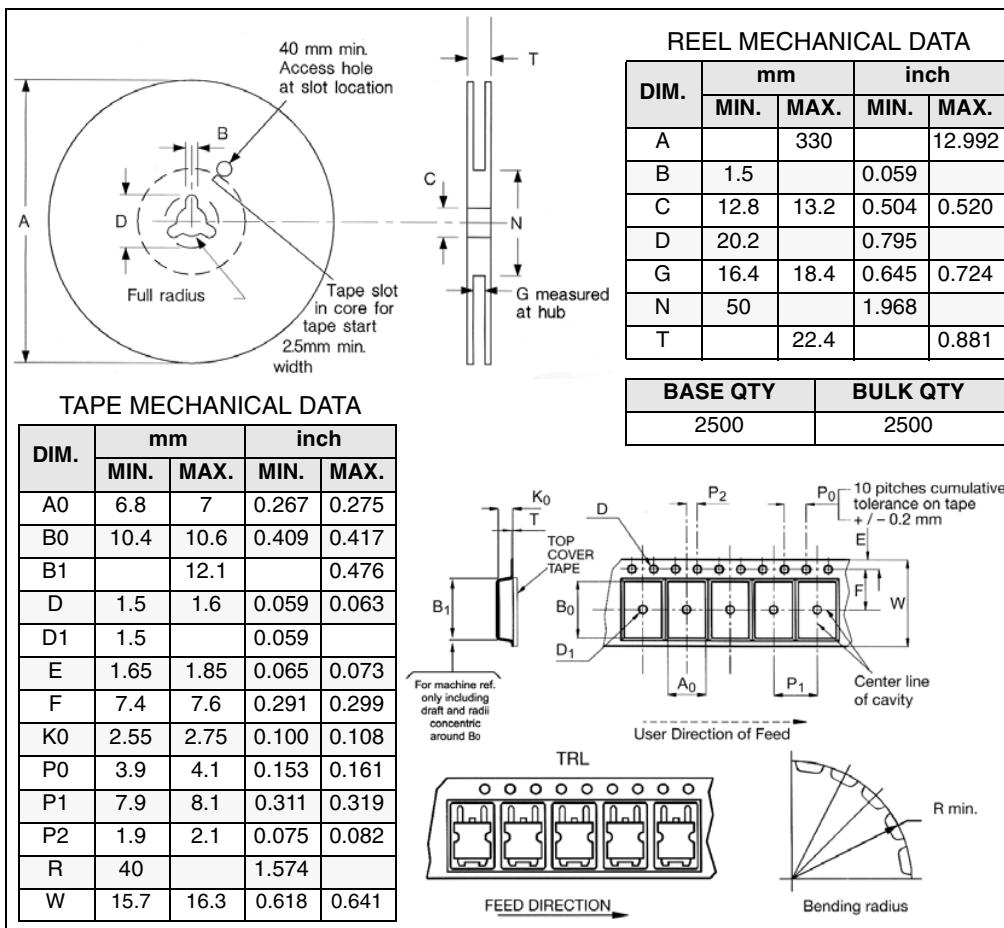


## 5 Packaging mechanical data

### DPAK FOOTPRINT



### TAPE AND REEL SHIPMENT



## 6 Revision history

**Table 8. Revision history**

Date	Revision	Changes
09-Sep-	3	Complete document
08-Aug-2006	4	New template, no content change
19-Feb-2007	5	Typo mistake on page 1

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